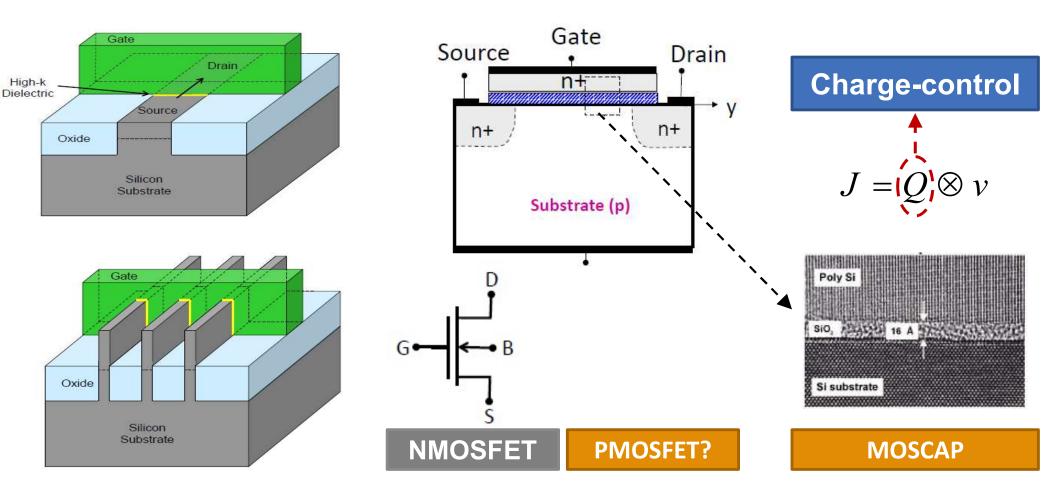
MOS Field-Effect Transistor (MOSFET)

MOS-based devices (MOSFET, FinFET, Power-MOSFET...)

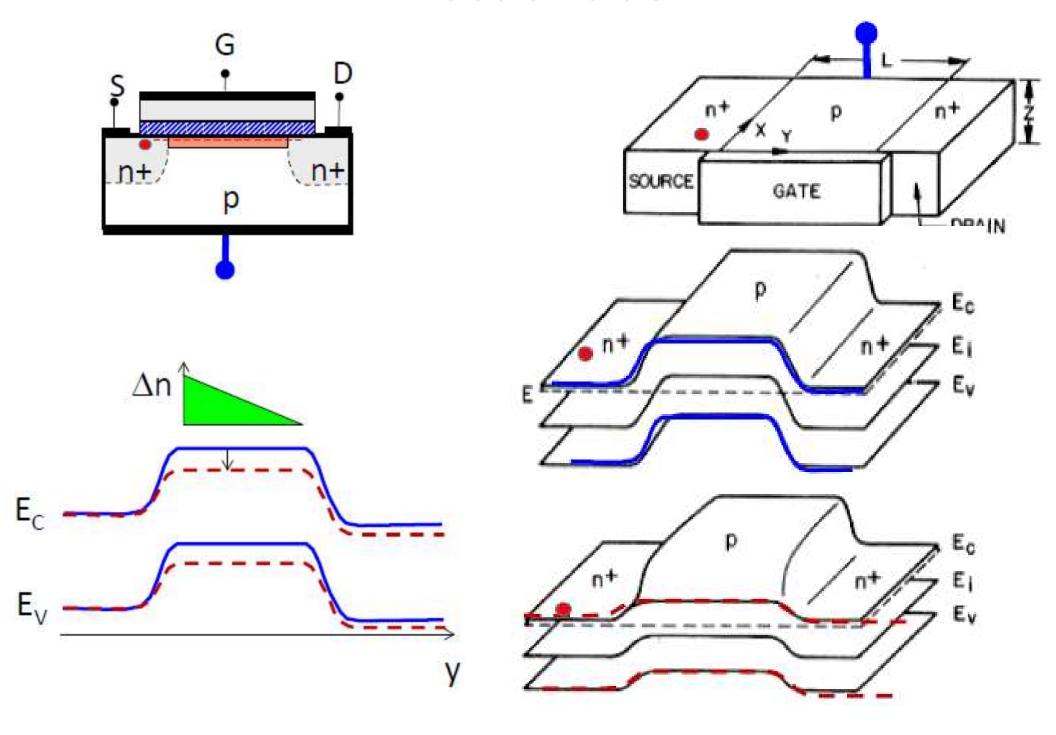
Low-power, integration



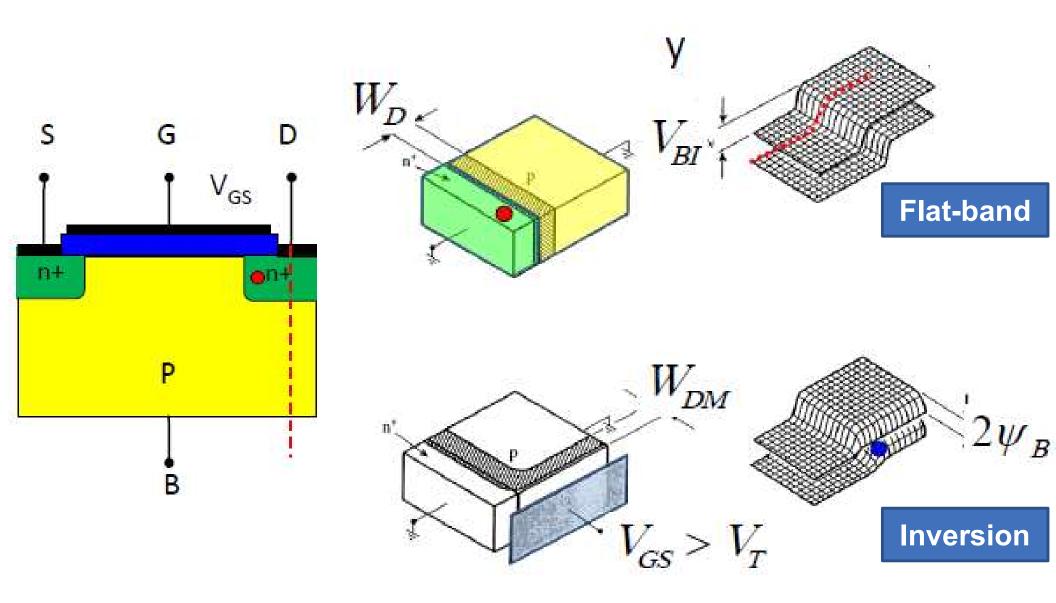
Digital logic/memory, analog, RF, power...



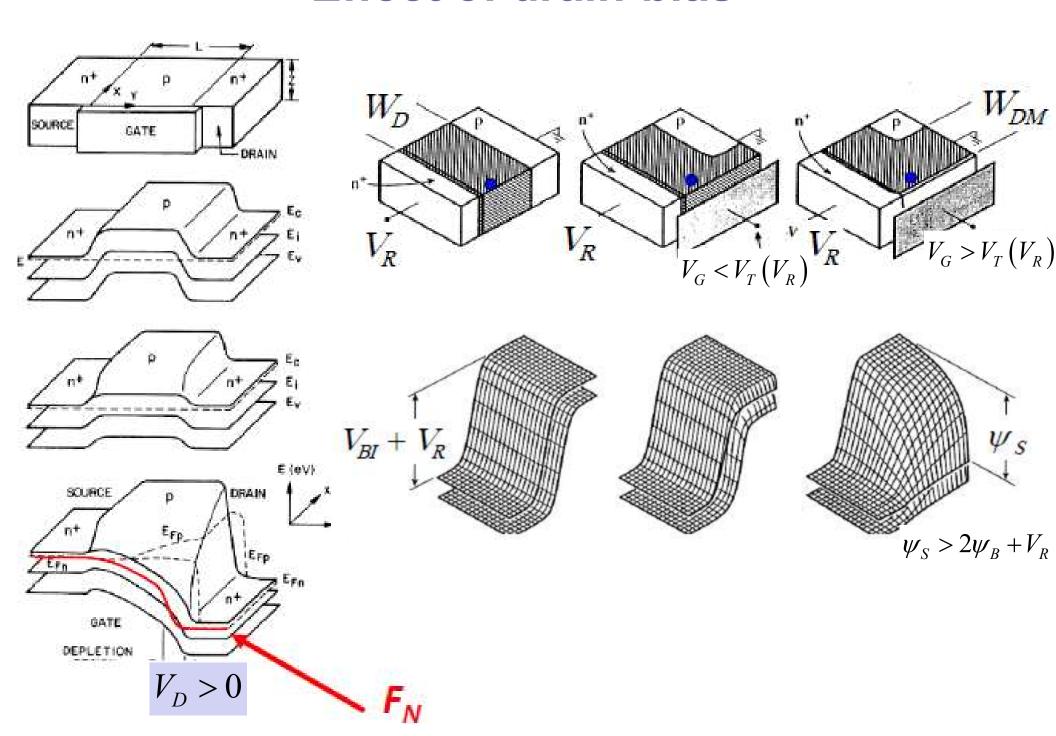
Effect of bias



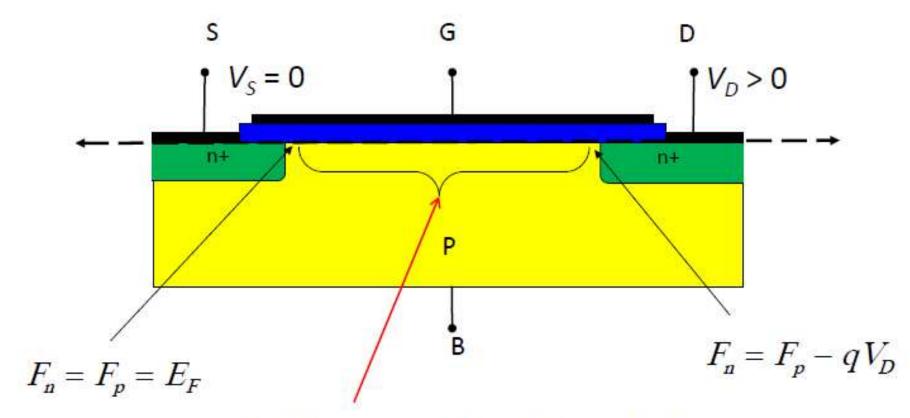
Effect of gate-bias



Effect of drain-bias



MOSFET I – V



 F_n increasingly negative from source to drain (reverse bias increases from source to drain)

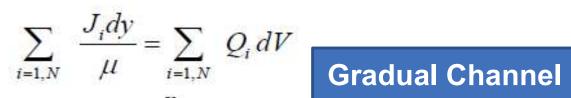
Depth-integrated current density

$$J_1 = Q_1 \mu \mathcal{E}_1 = Q_1 \mu \frac{dV}{dy} \bigg|_1$$

$$J_2 = Q_2 \mu \mathcal{E}_2 = Q_2 \mu \frac{dV}{dy} \bigg|_2$$

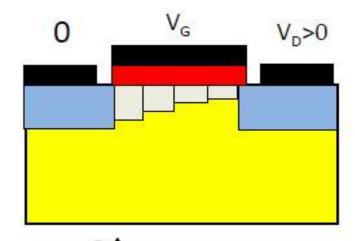
$$J_3 = Q_3 \mu \mathcal{E}_3 = Q_3 \mu \frac{dV}{dy} \bigg|_3$$

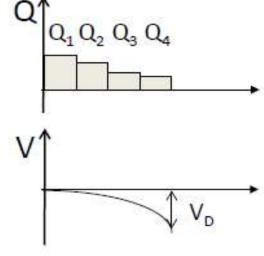
$$J_4 = Q_4 \mu \mathcal{E}_4 = Q_4 \mu \frac{dV}{dy} \bigg|_4$$



$$\frac{J_{D}}{\mu} \sum_{i=1,N} dy = \int_{0}^{V_{D}} C_{ox} (V_{G} - V_{th} - mV) dV$$

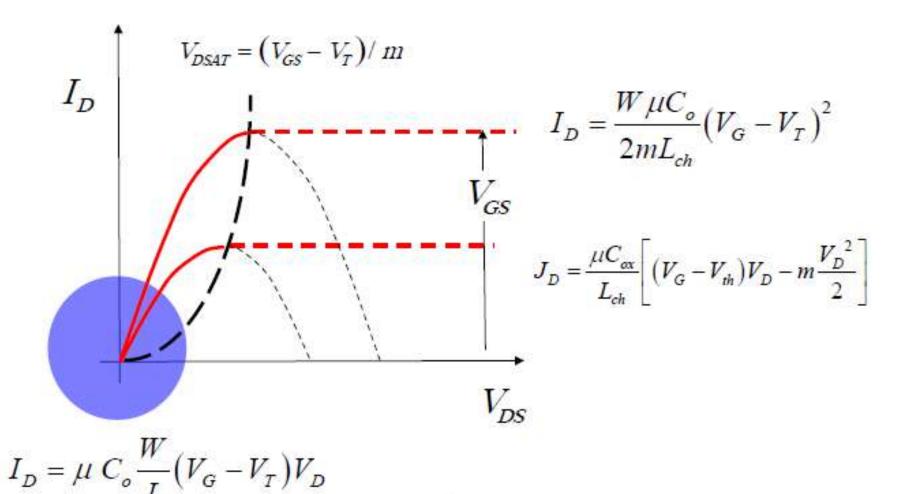
$$J_{D} = \frac{\mu C_{ox}}{L_{ch}} \left[(V_{G} - V_{th}) V_{D} - m \frac{V_{D}^{2}}{2} \right]$$



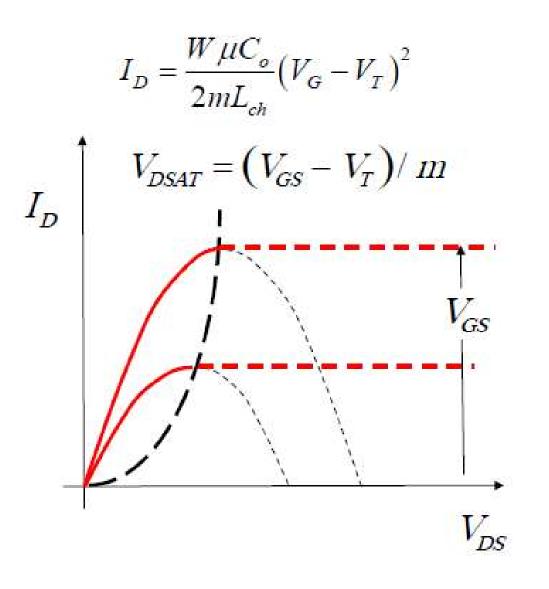


Square-law I-V

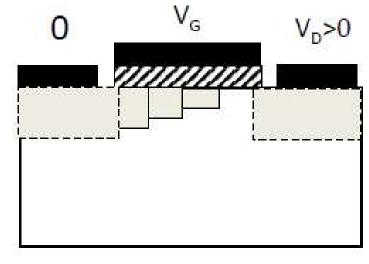
$$\begin{split} I_D &= W \frac{\mu C_{ox}}{L_{ch}} \bigg[(V_G - V_{th}) V_D - m \frac{{V_D}^2}{2} \bigg] \\ &\frac{dI_D}{dV} = 0 = (V_G - V_{th}) - m V_D \Rightarrow V_{D,sat} = ({V_G}^* - V_{th}) / m \end{split}$$

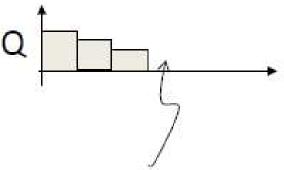


Saturation and pinch-off



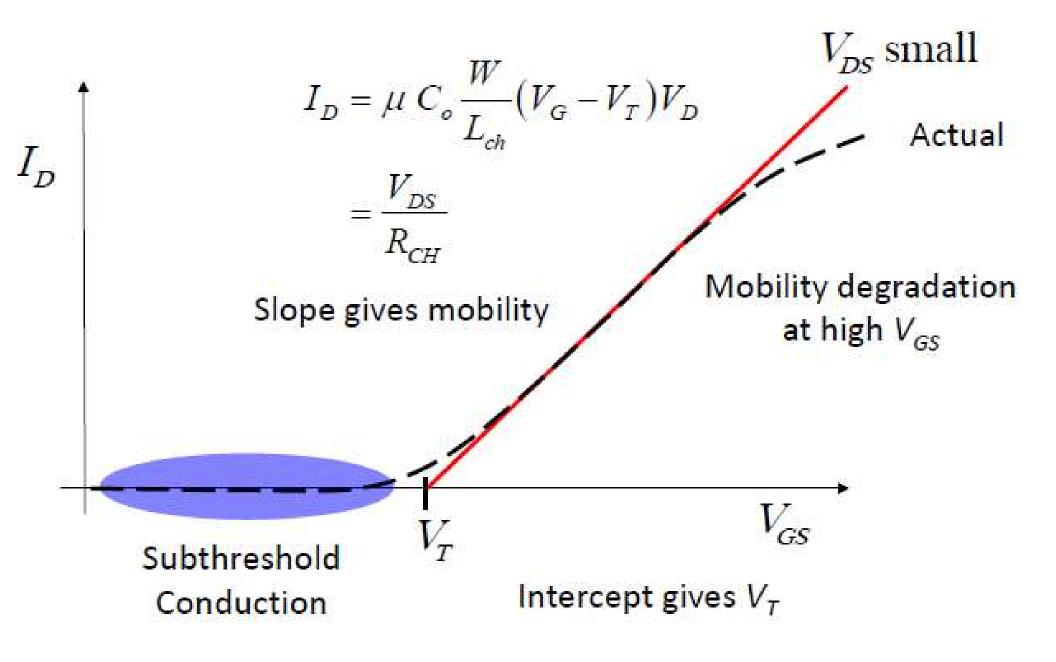
$$Q_i \approx -C_{ox}(V_G - V_{th} - mV)$$





loss of inversion

Linear region (low V_{DS})



Finis

Sources:

- 1. Prof. M.A. Alam
- 2. www.nature.com